1.1 Scope.

This specification covers the detail requirements for a 12-bit resolution A/D converter with complete microprocessor interface and a high performance reference.

1.2 Part Number.

The complete part number per Table 1 of this specification is as follows:

Device	Part Number[1]
– 1	AD674BT(X)/883B
– 2	AD774BT(X)/883B

NOTE
[1]See paragraph 1.2.3 for package identifier.

1.2.3 Case Outline.

See Appendix 1 of General Specification ADI-M-1000: package outline:

(X)	Package	Description
D	D-28	28-Pin Ceramic DIP

1.3 Absolute Maximum Ratings. (T_A = +25°C unless otherwise noted)

V_{CC} to Digital Common ..... +16.5 V
V_{EE} to Digital Common ..... −16.5 V
V_{LOGIC} to Digital Common ..... +7 V
Analog Common to Digital Common ..... ±1 V
Control Inputs (CE, $\overline{CS}$, A_0, 12/$\overline{8}$, R/$\overline{C}$) to Digital Common ..... −0.5 V to V_{LOGIC} +0.5 V
Analog Inputs (REF IN, BIP OFF, 10 V_{IN}) to Analog Common ..... V_{EE} to V_{CC}
20 V_{IN} to Analog Common ..... ±24 V
REF OUT ..... Indefinite Short to Common
Momentary Short to V_{CC}
Power Dissipation ..... 470 mW
Storage Temperature Range ..... −65°C to +150°C
Lead Temperature (Soldering 10 sec) ..... +300°C

1.5 Thermal Characteristics.

Thermal Resistance θ_{JC} = 25°C/W
θ_{JA} = 60°C/W

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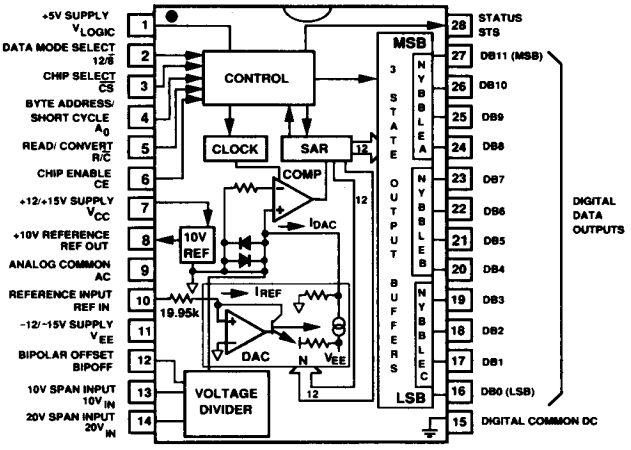
Table 1.

Test	Symbol	Device	Design Limit @+25°C	Sub Group 1	Sub Group 2, 3	Test Condition[1]	Unit
Power Dissipation	P_D	−1, 2	375	375	375	Tristated Outputs	mW max
Input Resistance	R_{IN}	−1, 2	3	3		10 V Span	kΩ min
			7	7			kΩ max
			6	6		20 V Span	kΩ min
			14	14			kΩ max
Internal Reference Output Voltage	V_{REF}	−1, 2	+9.9	+9.9		Bipolar 20 V Span 2.0 mA External Load	V min
			+10.1	+10.1			V max
Logic Input High Voltage CE, $\overline{CS}$, R/$\overline{C}$, A_0	V_{IH}	−1, 2	2.0	2.0	2.0		+V min
Logic Input Low Voltage CE, $\overline{CS}$, R/$\overline{C}$, A_0	V_{IL}	−1, 2	0.8	0.8	0.8		+V max
Logic Input Current CE, $\overline{CS}$, R/$\overline{C}$, A_0	I_{LIN}	−1, 2	10	10	10	V_{IH} = 5.0 V; V_{IL} = 0.0 V	±μA max
Logic Output High Voltage DB11–DB0	V_{OH}	−1, 2	2.4	2.4	2.4	I_{SOURCE} = 500 μA	+V min
Logic Output Low Voltage DB11–DB0, STS	V_{OL}	−1, 2	0.4	0.4	0.4	I_{SINK} = 1.6 mA	+V max
Three-State Output Leakage DB11–DB0	I_{OLT}	−1, 2	10	10	10	Outputs Tristated V_{IH} = 5.0 V	±μA max
Power Supply Current	I_L I_{CC} I_{EE}	−1, 2	7 7 14	7 7 14	7 7 14	Outputs Tristated REF OUT to REF IN Through 50 Ω	mA max
Integral Nonlinearity	INL	−1, 2	1/2	1/2	1	Major Transitions Unipolar 10 V Span Bipolar 20 V Span	±LSB max
Differential Nonlinearity[2]	DNL	−1, 2	12	12	12	All Codes Tested Unipolar 10 V Span Bipolar 20 V Span	Bits min
Power Supply Rejection[3]	PSR	−1, 2	1	1	1	See Note 4 Unipolar 10 V Span	±LSB max
			1/2	1/2	1/2	See Note 5	
			1	1	1	See Note 6	
Unipolar Offset Error	U_{OSE}	−1, 2	2	2		10 V Span	±LSB max
Unipolar Offset Drift	TCU_{OSE}	−1, 2			1	10 V Span	±LSB max
Bipolar Offet Error	B_{POE}	−1, 2	3	3		20 V Span	±LSB max
Bipolar Offset Drift	TCB_{POE}	−1, 2			2	20 V Span	±LSB max
Full-Scale Calibration Error	A_B	−1, 2	0.125	0.125		Bipolar 20 V Span	±% of FSR max
	A_U	−1, 2	0.125			Unipolar 10 V Span	
Full-Scale Calibration Drift	TCA_E	−1, 2			7	Bipolar 20 V Span	±LSB max

Test	Symbol	Device	Design Limit @+25°C	Sub Group 9	Sub Group 10, 11	Test Condition[1]	Unit
Conversion Time	t_C	−1	10	10	10	To 8-Bits	µs max
			15	15	15	To 12-Bits	µs max
		−2	6	6	6	To 8-Bits	µs max
			8	8	8	To 12-Bit	µs max
Converter Start Timing[7]							
STS Delay from CE	t_{DSC}	−1, 2	200	200	225	Timing per Figure 1	ns max
CE Pulse Width	t_{HEC}	−1, 2	50	50	50	Timing per Figure 1	ns min
$\overline{CS}$ to CE Setup	t_{SSC}	−1, 2	50	50	50	Timing per Figure 1	ns min
$\overline{CS}$ Low During CE High	t_{HSC}	−1, 2	50	50	50	Timing per Figure 1	ns min
R/$\overline{C}$ to CE Setup	t_{SRC}	−1, 2	50	50	50	Timing per Figure 1	ns min
R/$\overline{C}$ Low During CE High	t_{HRC}	−1, 2	50	50	50	Timing per Figure 1	ns min
A_0 to CE Setup	t_{SAC}	−1, 2	0	0	0	Timing per Figure 1	ns min
A_0 Valid During CE High	t_{HAC}	−1, 2	50	50	50	Timing per Figure 1	ns min
Read Timing–Full Control Mode[7]							
Access Time	t_{DD}	−1, 2	150	150	150	Load per Figure 3a	ns max
Data Valid After CE Low	t_{HD}	−1, 2	25	25	15	Timing per Figure 2	ns min
Output Float Delay	t_{HL}	−1, 2	150	150	150	Load per Figure 3b	ns max
$\overline{CS}$ to CE Setup	t_{SSR}	−1, 2	50	50	50	Timing per Figure 2	ns min
R/$\overline{C}$ to CE Setup	t_{SRR}	−1, 2	0	0	0	Timing per Figure 2	ns min
A_0 to CE Setup	t_{SAR}	−1, 2	50	50	50	Timing per Figure 2	ns min
$\overline{CS}$ Valid After CE Low	t_{HSR}	−1, 2	0	0	0	Timing per Figure 2	ns min
R/$\overline{C}$ High After CE Low	t_{HRR}	−1, 2	0	0	0	Timing per Figure 2	ns min
A_0 Valid After CE Low	t_{HAR}	−1, 2	50	50	50	Timing per Figure 2	ns min
Stand-Alone Mode Timing[7]							
Data Access Time	t_{DDR}	−1, 2	150	150	150	Timing per Figures 4a and 4b	ns max
Low R/$\overline{C}$ Pulse Width	t_{HRL}	−1, 2	50	50	50	Timing per Figures 4a and 4b	ns min
STS Delay from R/$\overline{C}$	t_{DS}	−1, 2	200	200	225	Timing per Figures 4a and 4b	ns max
Data Valid After R/$\overline{C}$ Low	t_{HDR}	−1, 2	25	25	25	Timing per Figures 4a and 4b	ns min
STS Delay After Data Valid	t_{HS}	−1, 2	30	30	30	Timing per Figures 4a and 4b	ns min
			600	600	600	Timing per Figures 4a and 4b	ns max
High R/$\overline{C}$ Pulse Width	t_{HRH}	−1, 2	150	150	150	Timing per Figures 4a and 4b	ns min

NOTES
[1]V_{CC} = +15 V, V_{EE} = −15 V, V_{LOGIC} = +5 V, 12/$\overline{8}$ connected to V_{LOGIC}, A_0 and $\overline{CS}$ at Logic "0," CE at Logic "1."
10 V Unipolar—50 Ω resistor Pin 8 to Pin 10, 50 Ω resistor Pin 12 to ground. Analog input connected to Pin 13.
20 V Bipolar—50 Ω resistor Pin 8 to Pin 12, 50 Ω resistor Pin 8 to Pin 10. Analog input connected to Pin 14.
See Figures 1, 2, 3 and 4 for timing information.
[2]Minimum resolution for which no missing codes are guaranteed.
[3]Change in the full-scale unipolar 10 V span as power supply voltage is varied from min to max specified value.
[4]Test conditions for PSRR: 13.5 V ≤ V_{CC} ≤ 16.5 V, V_{LOGIC} = 5 V, V_{EE} = −15 V; 11.4 V < V_{CC} ≤ 12.6 V, V_{LOGIC} = 5 V, V_{EE} = −12 V.
[5]4.5 V ≤ V_{LOGIC} ≤ 5.5 V, V_{CC} = 15 V, V_{EE} = −15 V.
[6]−16.5 V ≤ V_{EE} ≤ −13.5 V, V_{LOGIC} = 5 V, V_{CC} = 15 V; −12.6 V ≤ V_{EE} ≤ −11.4 V, V_{LOGIC} = 5 V, V_{CC} = 12 V.
[7]Timing tests are guaranteed from −55°C to +125°C.

3.2.1 Functional Block Diagram and Terminal Assignments.

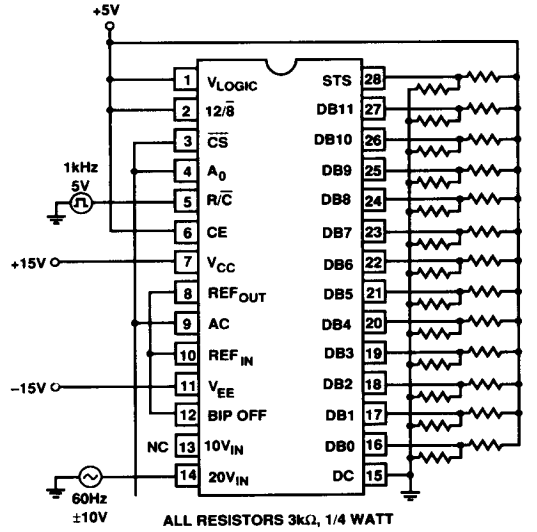


3.2.4 Microcircuit Technology Group.

This microcircuit is covered by technology group (57).

4.2.1 Life Test/Burn-In Circuit.

Steady state life test is per MIL-STD-883 Method 1005. Burn-in is per MIL-STD-883 Method 1015 Test Condition (B).



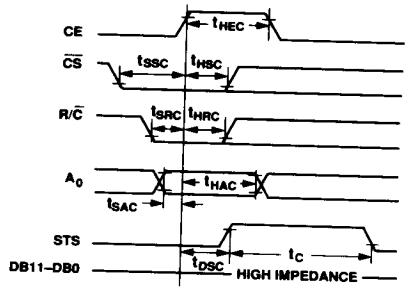


Figure 1. Converter Start Timing

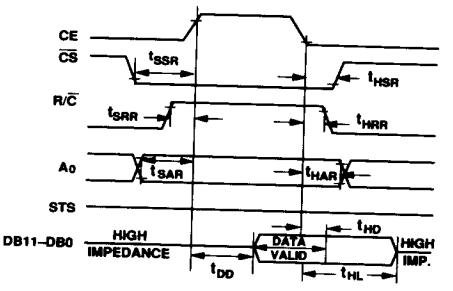


Figure 2. Read Timing

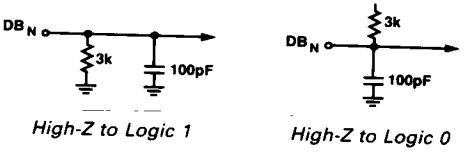


Figure 3a. Load Circuit for Access Time Test

Figure 3b. Load Circuit for Output Float Delay Test

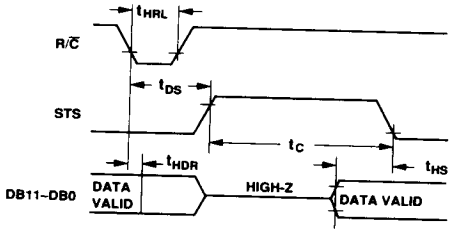


Figure 4a. Stand-Alone Mode Timing Low Pulse for R/C

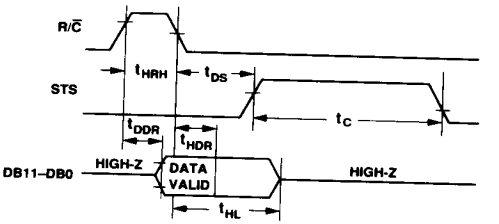


Figure 4b. Stand-Alone Mode Timing High Pulse for R/C

Table 2. AD674B/AD774BA Truth Table

CE	CS	R/C	12/8	A_0	Operation
0	X	X	X	X	None
X	1	X	X	X	None
1	0	0	X	0	Initiate 12-Bit Conversion
1	0	0	X	1	Initiate 8-Bit Conversion
1	0	1	1	X	Enable 12-Bit Parallel Output
1	0	1	0	0	Enable 8 Most Significant Bits
1	0	1	0	1	Enable 4 LSBs and 4 Trailing Zeroes